



## Comparing the Effects of Nb, Pb, Y, and La Replacement on the Structural, Electrical, and Magnetic Characteristics of Bi-Based Superconductors

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### Abstract

In this study, the effects of Pb, Nb, La, and Y replacements were investigated on Bi-based superconducting materials. In preparing the samples, we used a method called solid-state reaction method. The patterns of the X-ray diffraction of all samples indicated presence of Bi-2212 and Bi-2223 phases. The results obtained from XRD revealed that with increase of the melting point of substitution elements, the Bi-2223 phase decreased while the Bi-2212 phase and impurity phases of samples grew. From the electrical resistivity measurements using the four-probe method, it was found that sample A with Pb and sample B with La replacements had the maximum and minimum critical temperatures of 111.4 and 81.6 K, respectively. Based on hysteresis loop ( $M-H$ ) measurement using Bean's model, estimation of critical current density ( $J_c$ ) showed that sample A with Pb and sample B with La substitution had the maximum and minimum values respectively. These results may be due to the melting point of these elements with values of 888, 1512, 2315, and 2425 °C for PbO, Nb<sub>2</sub>O<sub>5</sub>, La<sub>2</sub>O<sub>3</sub>, and Y<sub>2</sub>O<sub>3</sub>, respectively. These elements were replaced by Bi<sub>2</sub>O<sub>3</sub> with a melting point of 817 °C. Further, the samples were prepared at the temperature of 845 °C. It seems at this temperature, these elements not only dissolve within the main matrix and participate in the formation of the Bi-2212 phase during the sintering process but they also participate in the development of the variety of the impurity phases as confirmed by XRD results.

**Keywords** Bi-based superconductors · Volume fraction · Critical temperature · Four-point probe method · Lattice parameters ·  $p$  parameter

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